

MSKSEMI 美森科

SEMICONDUCTOR



ESD



TVS



TSS



MOV



GDT



PLED

TL431ACxxx-MS

Product specification

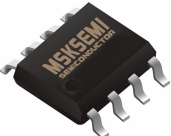
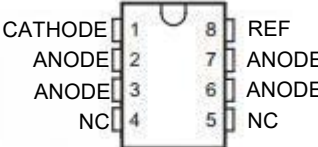
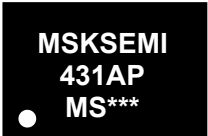
DESCRIPTION

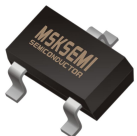
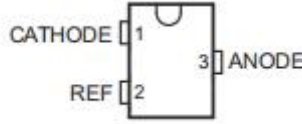

The TL431ACxxx-MS is a three-terminal adjustable regulator series with a guaranteed thermal stability over applicable temperature ranges. The output voltage may be set to any value between V_{ref} (approximately 2.5 volts) and 40 volts with two external resistors. These devices have a typical dynamic output impedance of 0.2Ω . Active output circuitry provides a very sharp turn-on characteristic, making these devices excellent replacement for zener diodes in many applications.

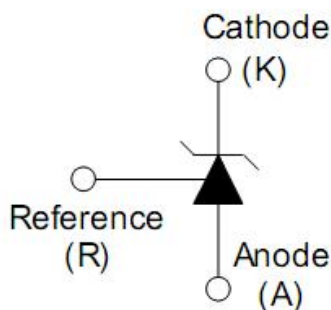
FEATURES

- Programmable Output Voltage to 36V
- Low Dynamic Output Impedance 0.27Ω (Typ)
- Sink Current Capability of 0.1 mA to 100 mA
- Equivalent Full-Range Temperature Coefficient of 50 ppm/°C
- Temperature Compensated for Operation over Full Rated Operating Temperature Range
- Low Output Noise Voltage
- Fast Turn on Respons
- SOP-8, SOT-23 packages

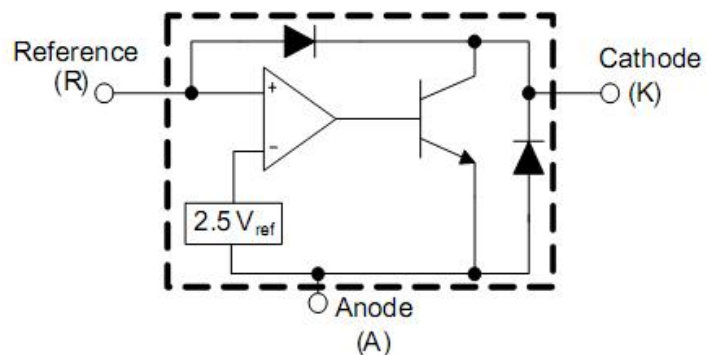
Reference News

SOP-8	PIN CONFIGURATION	MARKING
	 <p>CATHODE 1 8 REF ANODE 2 7 ANODE ANODE 3 6 ANODE NC 4 5 NC</p> <p>NC - No internal connection</p>	

SOT-23	PIN CONFIGURATION	MARKING
	 <p>CATHODE 1 3 ANODE REF 2</p>	



Symbol



Representative Block diagram

ORDER INFORMATION

P/N	PKG	QTY
TL431ACDT-MS	SOP-8	2500
TL431ACL3T-MS	SOT-23	3000

ABSOLUTE MAXIMUM RATINGS

(Operating temperature range applies unless otherwise specified)

Characteristic	Symbol	Value	Unit
Cathode Voltage	V_{KA}	36	V
Cathode Current Range (Continuous)	I_K	-100 ~ 150	mA
Reference Input Current Range	I_{REF}	-0.05 ~ +10	mA
Power Dissipation at 25°C: SOT – 23 – 3 Package ($R_{\theta JA} = 625^{\circ}\text{C/W}$)	P_D	0.2	W
Junction Temperature Range	T_J	-40 ~ 125	°C
Storage Temperature Range	T_{stg}	-65 ~ +150	°C

RECOMMENDED OPERATING CONDITIONS

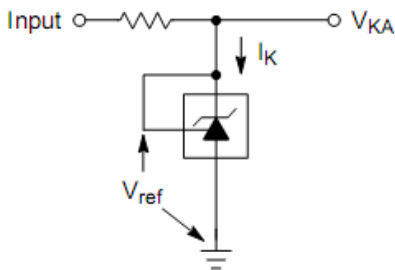
Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
Cathode Voltage	V_{KA}		V_{REF}		36	V
Cathode Current	I_K		0.5		100	mA

ELECTRICAL CHARACTERISTICS

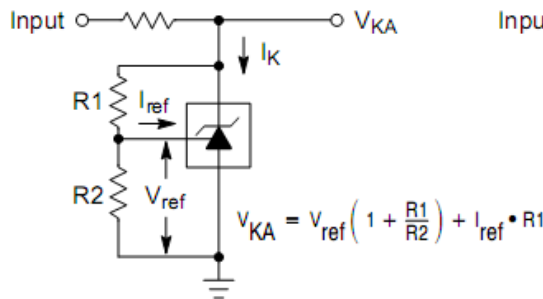
($T_a = 25^{\circ}\text{C}$, $V_{KA} = V_{REF}$, $I_K = 10\text{mA}$ unless otherwise specified)

Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
Reference Input Voltage	V_{REF}	$V_{KA} = V_{REF}$, $I_K = 10\text{mA}$	2.483	2.495	2.507	V
Deviation of Reference Input Voltage Over Full Temperature Range	$V_{REF(\text{dev})}$	$T_{\text{min}} \leq T_a \leq T_{\text{max}}$		3	17	mV
Ratio of Change in Reference Input Voltage to the Change in Cathode Voltage	$\Delta V_{REF}/\Delta V_{KA}$	$\Delta V_{KA} = 10\text{V}-V_{REF}$ $\Delta V_{KA} = 36\text{V}-10\text{V}$	-0.4 -0.4	0.0 0.0	2.7 2.0	mV/V
Reference Input Current	I_{REF}	$R_1 = 10\text{K}\Omega$, $R_2 = \infty$		1.8	4	μA
Deviation of Reference Input Current Over Full Temperature Range	$I_{REF(\text{dev})}$	$R_1 = 10\text{K}\Omega$, $R_2 = \infty$		0.4	1.2	μA
Minimum Cathode Current for Regulation	$I_{K(\text{min})}$			0.25	0.5	mA
Off-State Cathode Current	$I_{K(\text{off})}$	$V_{KA} = 40\text{V}$, $V_{REF} = 0$		0.17	0.9	μA
Dynamic Impedance	Z_{KA}	$I_K = 1\text{mA}$ 100 mA, $f \leq 1.0\text{KHz}$		0.27	0.5	Ω

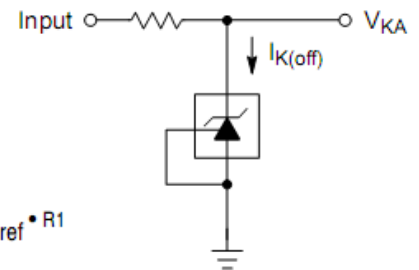
TEST CIRCUITS



Test Circuit
for $V_{KA} = V_{ref}$

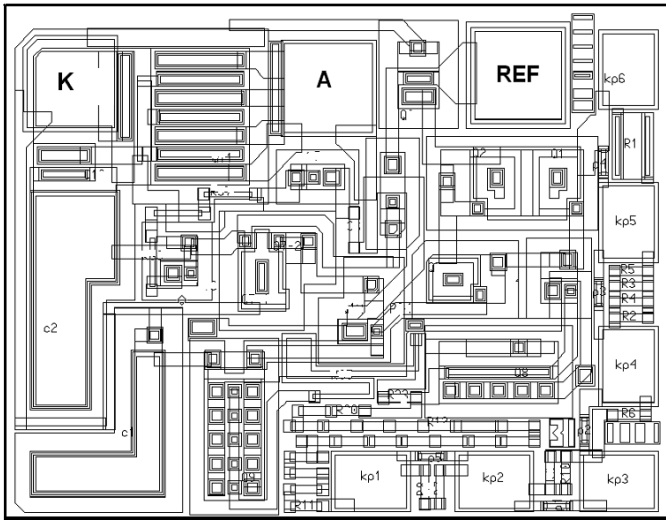


Test Circuit
for $V_{KA} > V_{ref}$



Test Circuit
for $I_{K(\text{off})}$

PAD LAYOUT



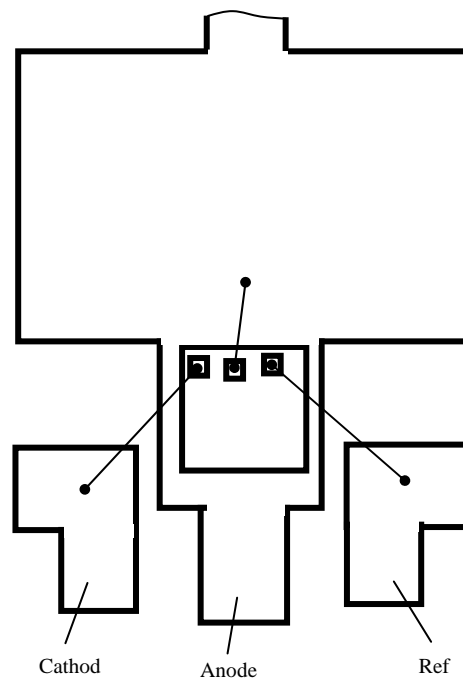
PHISICAL CHARACTERISTICS:

- Wafer Diameter.....100 ± 0.5mm
- Wafer Thickness..... 260 ±20 μm
- Die size.....0.76 x 0.60 mm²
- Scribe Width.....60 μm
- Pad Size86 x 86 μm
- Passivation.....PECVD
- Backside metallizationwithout metallization

PAD LOCATION

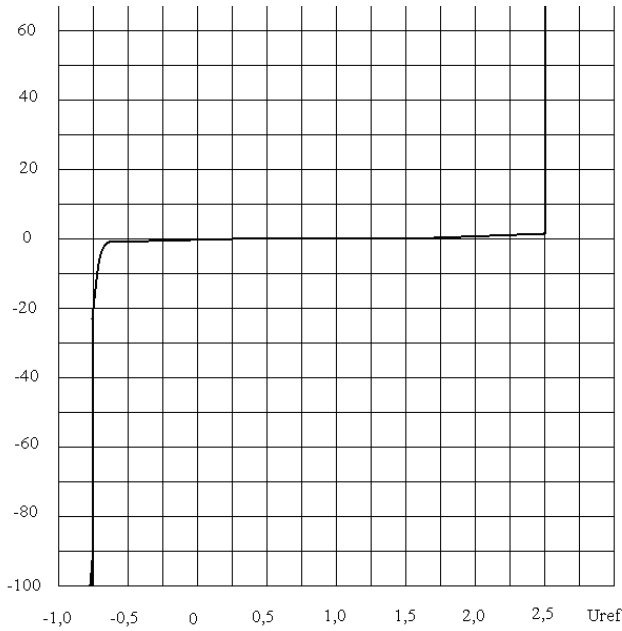
Pad Name	Description	X	Y
K	Cathode	56	445
A	Anode	328	440
R	Reference	528	453

BONDING DIAGRAM

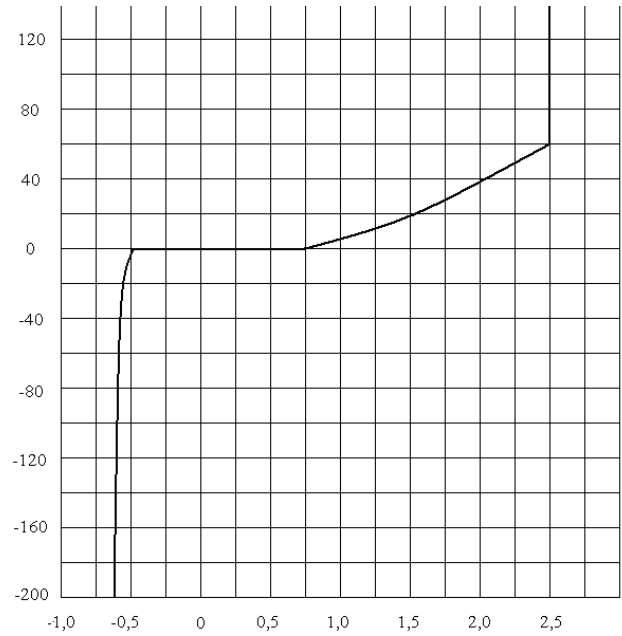


TYPICAL PERFORMANCE CHARACTERISTICS

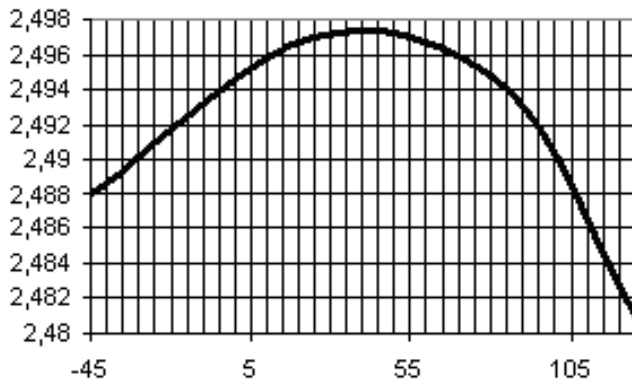
**Cathode Current I_k (mA)
vs. Cathode Voltage U_k (V)**



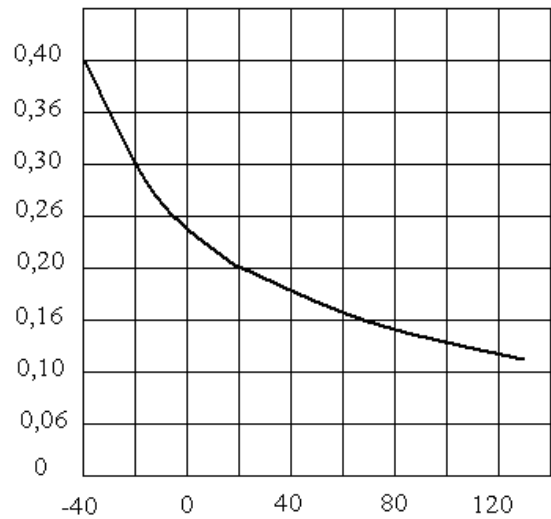
**Cathode Current I_k (μ A)
vs. Cathode Voltage U_k (V)**



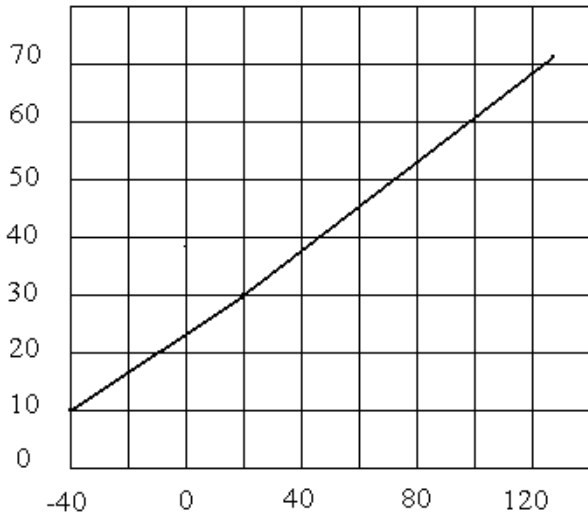
**Reference Voltage U_{ref} (V)
vs. Junction Temperature T_j ($^{\circ}$ C)
 $I_k=10\text{mA}$**



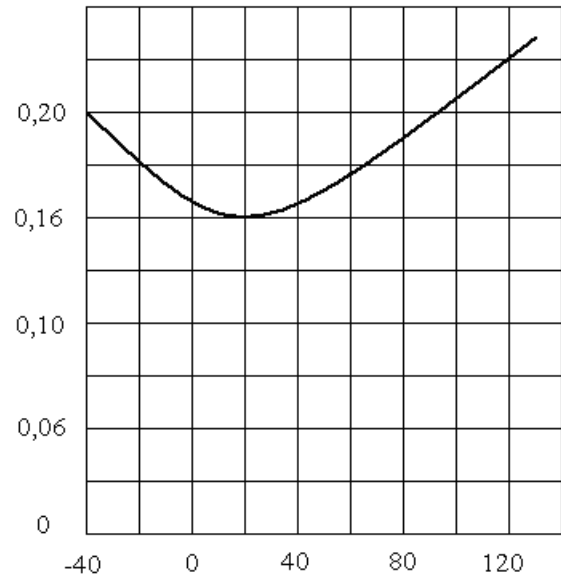
**Reference Input Current I_{ref} (μ A)
vs. Junction Temperature T_j ($^{\circ}$ C)
 $I_k=10\text{mA}$**



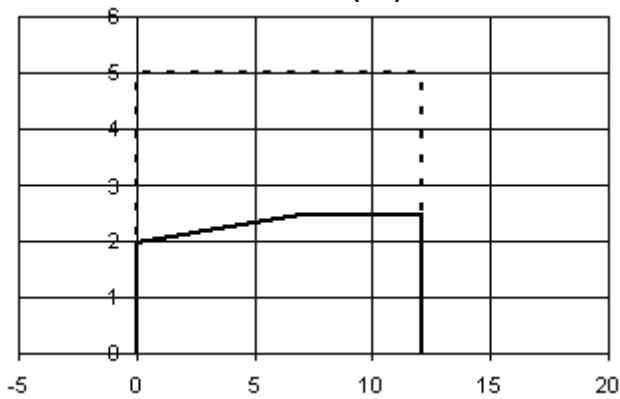
**Off-State Cathode Current I_{koff} (μA)
vs. Junction Temperature T_j ($^{\circ}C$)
 $U_{ka}=36V$**



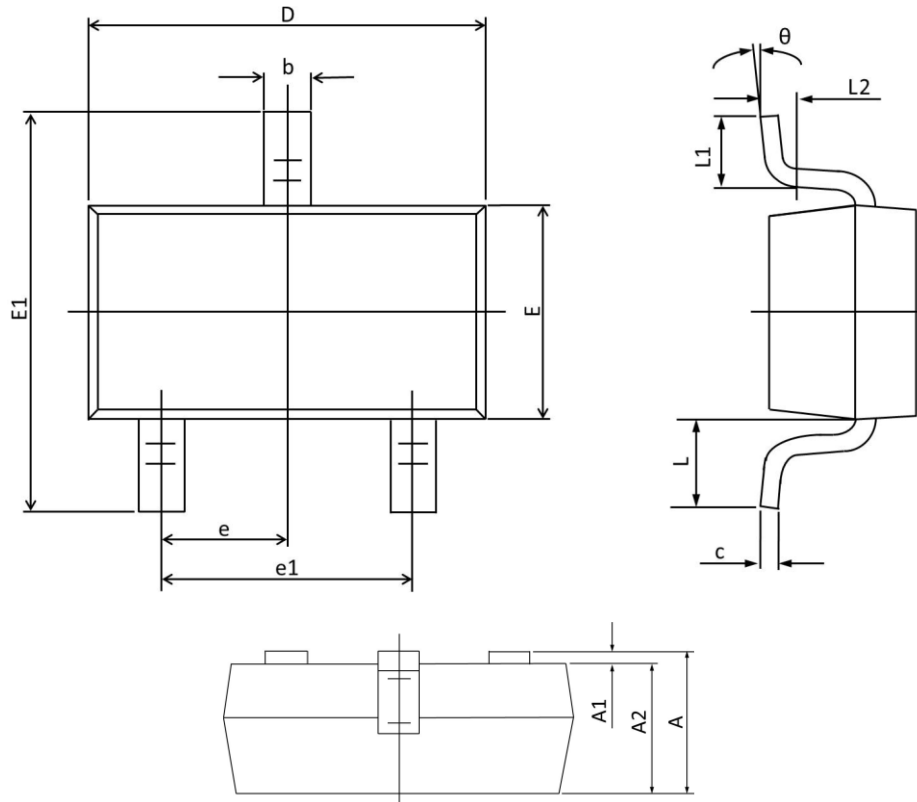
**Dynamic Impedance Z_{ka} (Ohm)
vs. Junction Temperature T_j ($^{\circ}C$)
 $I_k = 1 \div 100$ mA**



**Pulse Response Input and Output Voltage (V)
vs. Time t (μS)**

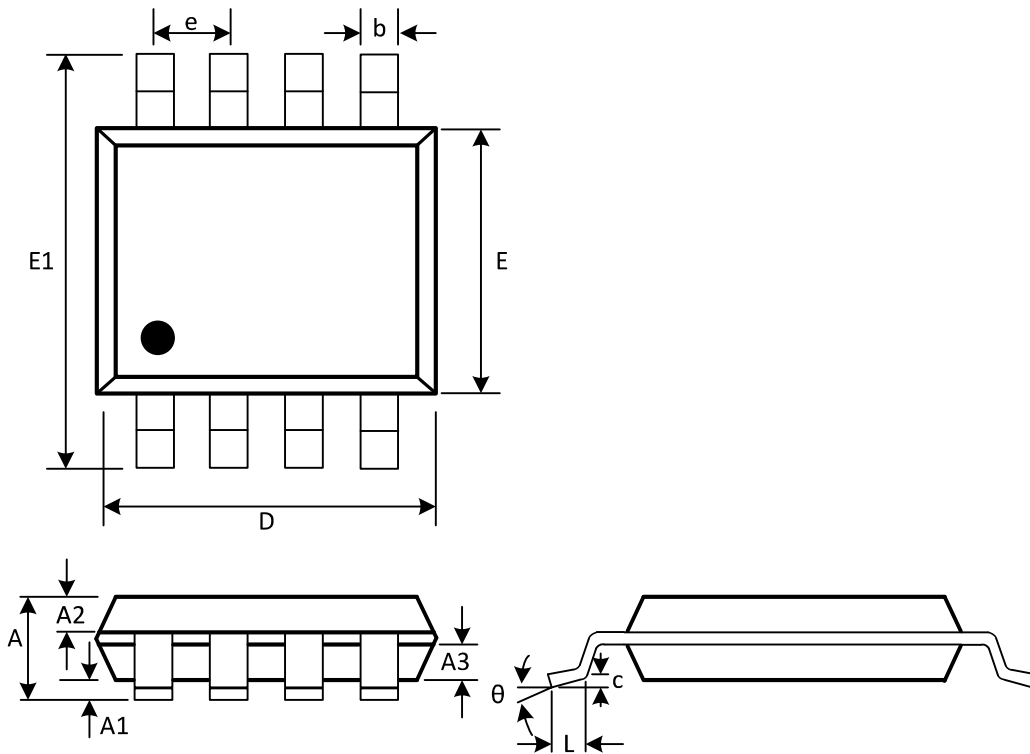


SOT-23 PACKAGE INFORMATION



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Max	Min	Max	Min
A	1.150	0.900	0.045	0.035
A1	0.100	0.000	0.004	0.000
A2	1.050	0.900	0.041	0.035
b	0.500	0.300	0.020	0.012
c	0.150	0.080	0.006	0.003
D	3.000	2.800	0.118	0.110
E	1.400	1.200	0.055	0.047
E1	2.550	2.250	0.100	0.089
e	0.95 TYP.		0.037 TYP.	
e1	2.000	1.800	0.079	0.071
L	0.55 REF.		0.022 REF.	
L1	0.500	0.300	0.020	0.012
L2	0.25 TYP.		0.01 TYP.	
θ	8°	0°	8°	0°

SOP-8 PACKAGE MECHANICAL DATA



(Unit: mm)

Symbol	Min	Max
A	1.300	1.600
A1	0.050	0.200
A2	0.550	0.650
A3	0.550	0.650
b	0.356	0.456
c	0.203	0.233
D	4.800	5.000
e	1.270(BSC)	
E	3.800	4.000
E1	5.800	6.200
L	0.400	0.800
θ	0°	8°

Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all MSKSEMI Semiconductor products described or contained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- MSKSEMI Semiconductor strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringement of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the MSKSEMI Semiconductor product that you intend to use.